

RefMat No



Included in
COMAR Database:
Green 1 --> YES
Blue 0 --> NO

Category 1	Film Thickness
Category 2	Depth profiling resolutio
Category 3	
Category 4	
Category 5	

Type_of_RefMat:

Name of RM: **NMIJ CRM 5202-a**

Description **SiO₂/Si Multilayer Film Reference Material; consist of five layers with SiO₂ and Si grown using r.f. magnetron sputtering method on a Si substrate. The thickness of each layer is certified in units of length via X-ray reflectometry. control the precision of analysis and to regulate measurement condition in depth profile analysis by ion**

Link http://www.nmij.jp/english/service/C/crm/2_E.pdf

Certified Quantities						
Film Thickness	MeanValue	20	nm	Uncertainty	0,6	nm
	MeanValue		nm	Uncertainty		
	MeanValue		nm	Uncertainty		
	MeanValue		nm	Uncertainty		
	MeanValue		nm	Uncertainty		

Calibration of	AES
Calibration of	ESCA
Calibration of	SIMS
Calibration of	ToF-SIMS
Calibration of	

Characterised by	grazing incidence x-ray refle
Characterised by	
Characterised by	
Characterised by	
Characterised by	

2 Provider

Provider No

Provider No	<input type="text" value="16"/>	Web address	<input type="text" value="http://www.nmij.jp/english/"/>
Provider	NMIJ (National Metrology Institute of Japan); AIST Tsukuba Central 5		
Contact Person	<input type="text" value="Reference Materials Office"/>	Country	<input type="text" value="Japan"/>
Email	<input type="text"/>	City	<input type="text" value="Tsukuba, Ibaraki"/>
Phone	<input type="text" value="+81-29-861-4059"/>	City Code	<input type="text" value="305-8565"/>
		Street + No	<input type="text" value="1-1-1 Higashi"/>